

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	31	US-6205472-\$.DID. OR US-6195657-\$.DID. OR US-6128646-\$.DID. OR US-0615709-\$.DID. OR US-6044354-\$.DID. OR US-6038543-\$.DID. OR US-6038537-\$.DID. OR US-6026148-\$.DID. OR US-5948054-\$.DID. OR US-5924072-\$.DID. OR US-5890132-\$.DID. OR US-5875431-\$.DID. OR US-5862223-\$.DID. OR US-5706452-\$.DID. OR US-5557515-\$.DID. OR US-5006998-\$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 11:54
L2	1511	706/45	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 11:54
L5	1511	2 and ad<"20011129"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:08
L6	530	706/11	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:08
L7	530	6 and ad<"20011129"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:14
L8	382	706/14	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:14
L9	382	8 and ad<"20011129"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:21
L10	1226	computer and user and expert and manager and knowledge and document and security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 12:19

L11	418	10 and team and capture	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 12:20
L13	311	11 and @ad<"20011129"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 12:21
S3	2	"20030229529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/08 11:47

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office
IEEE Xplore®
1 Million Documents
1 Million Users
...And Growing
» [Search Results](#)[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#) **Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1124699** documents.
A maximum of **500** results are displayed, **50** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

[Search](#)☐ Check to search within this result set**Results Key:**

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:

No documents matched your query.

[Print Format](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

 IEEE Xplore®
 1 Million Documents
 1 Million Users
 ...And Growing
 » Search Results

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **7** of **1124699** documents.
 A maximum of **500** results are displayed, **50** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set
Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard
1 An architecture for active DSS
Manheim, M.L.;

System Sciences, 1988. Vol.III. Decision Support and Knowledge Based Systems Track, Proceedings of the Twenty-First Annual Hawaii International Conference on , Volume: 3 , 5-8 Jan. 1988
 Pages:356 - 365

[\[Abstract\]](#) [\[PDF Full-Text \(632 KB\)\]](#) IEEE CNF
2 NASA Goddard Space Flight Center Virtual System Design Environment
Mapar, J.; Brown, K.; Medina, J.; Laskey, K.; Conaty, C.;

Aerospace Conference, 2001, IEEE Proceedings. , Volume: 7 , 10-17 March 2001
 Pages:7 - 3580 vol.7

[\[Abstract\]](#) [\[PDF Full-Text \(2876 KB\)\]](#) IEEE CNF
3 Evaluation of a generic expert system for corporate real estate disposition
Lipp, A.; Nourse, H.O.; Watson, H.J.; Bostrom, R.P.; Gatewood, R.D.;

System Sciences, 1994. Vol.III: Information Systems: Decision Support and Knowledge-Based Systems, Proceedings of the Twenty-Seventh Hawaii International Conference on , Volume: 3 , 4-7 Jan. 1994
 Pages:163 - 172

[\[Abstract\]](#) [\[PDF Full-Text \(764 KB\)\]](#) IEEE CNF
4 An expert system for ISO 9000 quality management system
Cheng, L.L.; Tsang, W.M.; Yeung, K.L.;

TENCON '93. Proceedings. Computer, Communication, Control and Power Engineering.1993 IEEE Region 10 Conference on , Issue: 0 , 19-21 Oct. 1993

Pages:726 - 729 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(240 KB\)\]](#) IEEE CNF

5 Knowledge-based decision support for ATE acquisition

Herren, L.T.; Rasti, M.;

AUTOTESTCON '92. IEEE Systems Readiness Technology Conference, Conference Record , 21-24 Sept. 1992

Pages:369 - 372

[\[Abstract\]](#) [\[PDF Full-Text \(276 KB\)\]](#) IEEE CNF

6 GOST: an active modeling system for costing and planning NASA space programs

Castillo, D.G.; Dolk, D.R.; Kridel, D.J.;

System Sciences, 1991. Proceedings of the Twenty-Fourth Annual Hawaii International Conference on , Volume: iii , 8-11 Jan. 1991

Pages:396 - 406 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(936 KB\)\]](#) IEEE CNF

7 Code generation tools for Windows/PM development

Baker, S.J.;

Software Tools for Windows-Based Application Development, IEE Colloquium on , 2 Mar 1990

Pages:4/1 - 4/2

[\[Abstract\]](#) [\[PDF Full-Text \(120 KB\)\]](#) IEE CNF

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved